

# Solving Bayesian Inference

How to get the posterior?

- analytical solution / closed-form solution

Beta as prior, Binomial as likelihood  $\rightarrow$  Beta

Gaussian as prior, Gaussian as likelihood  $\rightarrow$  Gaussian

- numerical solution / approximate solution
- direct sampling from distribution

For example, Metropolis Hastings algorithm from MCMC family can sample the posterior given a function  $f$  whose value is proportional to the posterior.

Incidentally, we know that,

$$f(x) = \text{prior}(x)\text{likelihood}(x) \propto \text{posterior}(x)$$

## Hypothesis Testing

Hypothesis is an assertion or a statement (about parameters). Hypothesis testing is about telling the significance of the statement.

If you can give a good interval estimation on the parameter, then the significance is easy to derive.

### Neyman-Pearson Method

#### Establish the Hypothesis

null hypothesis  $H_0$ , alternative hypothesis  $H_1$ .  $H_0$  and  $H_1$  are disjoint.

$$H_0 : \theta = \theta_0$$

1.  $H_1 : \theta \neq \theta_0$ , double-sided test
2.  $H_1 : \theta > \theta_0$ , single-sided test
3.  $H_1 : \theta < \theta_0$ , single-sided test

#### Establish the Rejection Region

If samples belong to rejection region  $W$ , we reject the null hypothesis.

Let  $\hat{\theta}$  be a point estimator of  $\theta$ . Let  $c > 0$ . When  $H_1$  is double-sided test.

$$W = \{(x_1, \dots, x_n) \mid |\hat{\theta} - \theta_0| > c\}$$

When  $H_1 : \theta > \theta_0$ ,

$$W = \{(x_1, \dots, x_n) | \hat{\theta} - \theta_0 > c\}$$

When  $H_1 : \theta < \theta_0$ ,

$$W = \{(x_1, \dots, x_n) | \hat{\theta} - \theta_0 < c\}$$

### Set up the Significance Level

	Judge: Accept $H_0$	Judge: Reject $H_0$
Fact: $H_0$ holds	Correct	Type I Mistake
Fact: $H_1$ holds	Type II Mistake	Correct

We cannot reduce the number of Type I and Type II mistakes at the same time. Usually we choose to reduce the number of Type I mistakes. The chance of Type I mistake is a probability:

$$P((x_1, \dots, x_n) \in W; \theta = \theta_0)$$

We want this probability to be smaller than a pre-set value  $\alpha$ , which is called the significance level. Suppose we are doing double-sided test.

$$W = \{(x_1, \dots, x_n) | |\hat{\theta} - \theta_0| > c\}$$

The significance level is the believed threshold probability of an improbable event.

## Supervised Learning

### Bayes Classifier

Bayes classifier is a supervised, generative classification model. In generative model,  $p(y)$ ,  $p(x|y)$  are learned.  $p(y)$  is a categorical distribution whose best estimation is just the frequencies.

### Naive Bayes Classifier

In naive Bayesian classifier, we assume a conditional independence for the random vector  $x$  given  $y$ .

$$p(x|y) = p(x_1|y)p(x_2|y) \dots p(x_n|y)$$

Further, we assume that all  $p(x_i|y)$  observes the same kind of distribution (in total,  $m \times n$  such distributions, where  $m$  is the number of different classes). This distribution can be Bernoulli distribution, multinomial distribution, Gaussian distribution, giving Bernoulli naive Bayes, multinomial naive Bayes, Gaussian naive Bayes.

## **Logistic Regression**

Logistic regression is a supervised, discriminative, binary classification model. In discriminative model,  $p(y|x)$  is learned.